

Abstract

The invention relates to a scanning microscope, comprising a light source (1), providing evanescent wave illumination for a sample (15), arranged on an object support (13). A point detector (35, 36) receives detection light (51), emitted from a raster point of the sample (15), whereby a beam diversion device (29) is arranged in the beam path of the detection light, by means of which the position of the raster point in the sample may be displaced.